

<b>Notice of References Cited</b>	Application/Control No. 10/751,521	Applicant(s)/Patent Under Reexamination TAKENAKA, HIROSHI	
	Examiner Ha T. Nguyen	Art Unit 2812	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,588,005 B1	07-2003	Kobayashi et al.	716/12
*	B	US-6,136,517 A	10-2000	Fletcher, Christopher L.	430/394
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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